

RoHS Compliant Product
A suffix of "-C" specifies halogen free

DESCRIPTION

The SSG10N10 is the highest performance trench N-ch MOSFETs with extreme high cell density , which provide excellent $R_{DS(on)}$ and gate charge for most of the synchronous buck converter applications .

FEATURES

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

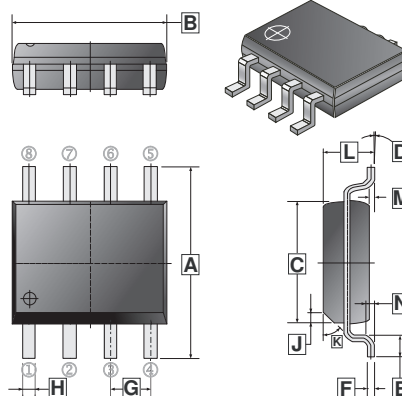
MARKING



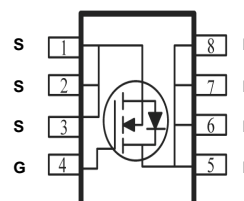
PACKAGE INFORMATION

Package	MPQ	Leader Size
SOP-8	3K	13 inch

SOP-8



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	H	0.35	0.49
B	4.80	5.00	J	0.375 REF.	
C	3.80	4.00	K	45°	
D	0°	8°	L	1.35	1.75
E	0.40	0.90	M	0.10	0.25
F	0.19	0.25	N	0.25 REF.	
G	1.27 TYP.				



ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ¹	I_D	$T_A=25^\circ\text{C}$	10
		$T_A=70^\circ\text{C}$	7.5
Pulsed Drain Current ²	I_{DM}	50	A
Total Power Dissipation @ $T_A=25^\circ\text{C}$ ⁴	P_D	1.6	W
Single Pulse Avalanche Energy ³	E_{AS}	98	mJ
Single Pulse Avalanche Current	I_{AS}	41	A
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~150	$^\circ\text{C}$
Thermal Resistance Rating			
Maximum Thermal Resistance Junction-Ambient ¹	$R_{\theta JA}$	80	$^\circ\text{C} / \text{W}$

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Teat Conditions	
Static							
Drain-Source Breakdown Voltage	BV_{DSS}	100	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$	
Gate-Threshold Voltage	$V_{GS(th)}$	2.5	-	4.5	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS}=\pm 20\text{V}$	
Drain-Source Leakage Current	I_{DSS}	$T_J=25^\circ\text{C}$	-	-	1	μA	$V_{DS}=80\text{V}, V_{GS}=0$
		$T_J=55^\circ\text{C}$	-	-	5		$V_{DS}=80\text{V}, V_{GS}=0$
Static Drain-Source On-Resistance ²	$R_{DS(ON)}$		-	-	21	m Ω	$V_{GS}=10\text{V}, I_D=10\text{A}$
			-	-	30		$V_{GS}=7\text{V}, I_D=6\text{A}$
Total Gate Charge ²	Q_g	-	27.6	-	nC	$I_D=7\text{A}$ $V_{DS}=80\text{V}$ $V_{GS}=10\text{V}$	
Gate-Source Charge	Q_{gs}	-	11.4	-			
Gate-Drain ("Miller") Change	Q_{gd}	-	7.9	-			
Turn-on Delay Time ²	$T_{d(on)}$	-	15.6	-	nS	$V_{DS}=50\text{V}$ $I_D=7\text{A}$ $V_{GS}=10\text{V}$ $R_L=3.3\Omega$	
Rise Time	T_r	-	17.2	-			
Turn-off Delay Time	$T_{d(off)}$	-	16.8	-			
Fall Time	T_f	-	9.2	-			
Input Capacitance	C_{iss}	-	1890	-	pF	$V_{GS}=0$ $V_{DS}=15\text{V}$ $f=1.0\text{MHz}$	
Output Capacitance	C_{oss}	-	268	-			
Reverse Transfer Capacitance	C_{rss}	-	67	-			
Guaranteed Avalanche Characteristics							
Single Pulse Avalanche Energy ⁵	EAS	53	-	-	mJ	$V_{DD}=25\text{V}, L=0.1\text{mH}, I_{AS}=30\text{A}$	
Source-Drain Diode							
Diode Forward Voltage ²	V_{SD}	-	-	1.2	V	$I_S=1\text{A}, V_{GS}=0, T_J=25^\circ\text{C}$	
Continuous Source Current ^{1,6}	I_S	-	-	10	A	$V_D=V_G=0, \text{Force Current}$	
Pulsed Source Current ^{2,6}	I_{SM}	-	-	50	A		
Reverse Recovery Time	T_{rr}	-	34	-	nS	$I_F=7\text{A}, di/dt=100\text{A}/\mu\text{s}, T_J=25^\circ\text{C}$	
Reverse Recovery Charge	Q_{rr}	-	47	-	nC		

Notes:

- The data tested by surface mounted on a 1 inch² FR-4 board with 2_{oz} copper. 125^oC/W when mounted on Min. copper pad.
- The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- The EAS data shows Max. rating . The test condition is $V_{DD}=25\text{V}, V_{GS}=10\text{V}, L=0.1\text{mH}, I_{AS}=41\text{A}$
- The power dissipation is limited by 150^oC, junction temperature
- The Min. value is 100% EAS tested guarantee.
- The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

CHARACTERISTIC CURVES

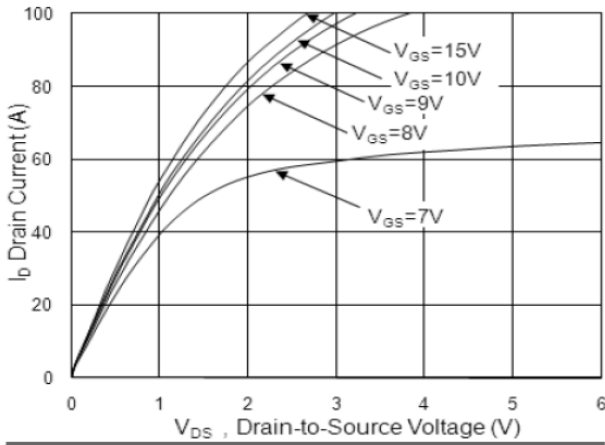


Fig.1 Typical Output Characteristics

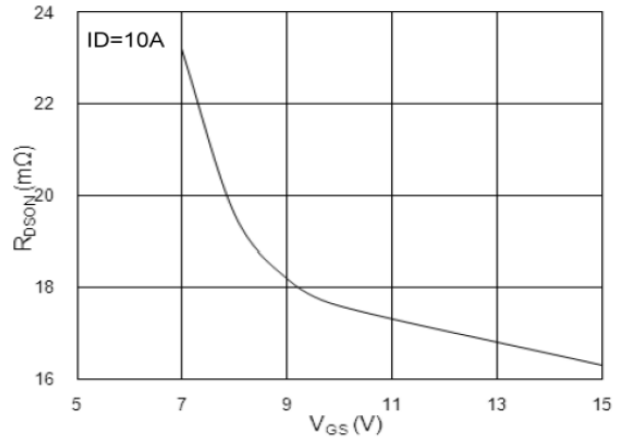


Fig.2 On-Resistance v.s Gate-Source

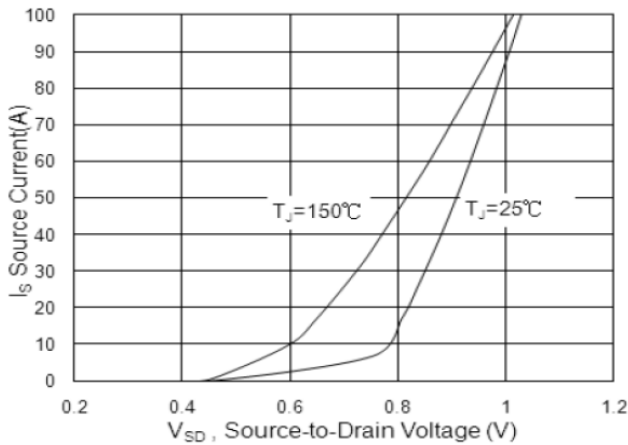


Fig.3 Forward Characteristics of Reverse

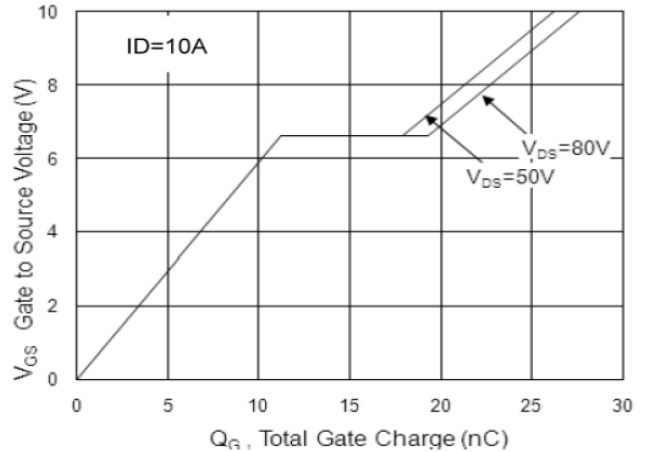


Fig.4 Gate-Charge Characteristics

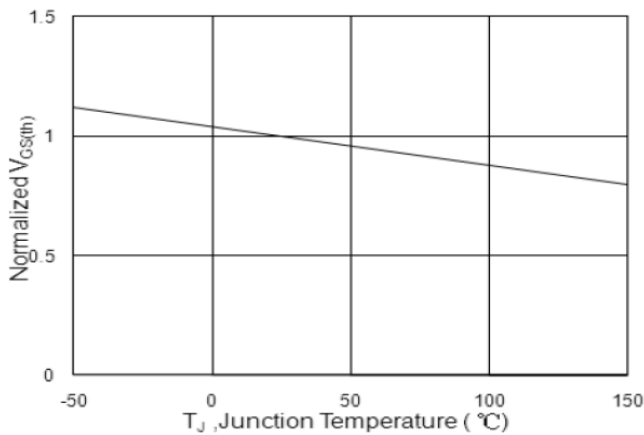


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

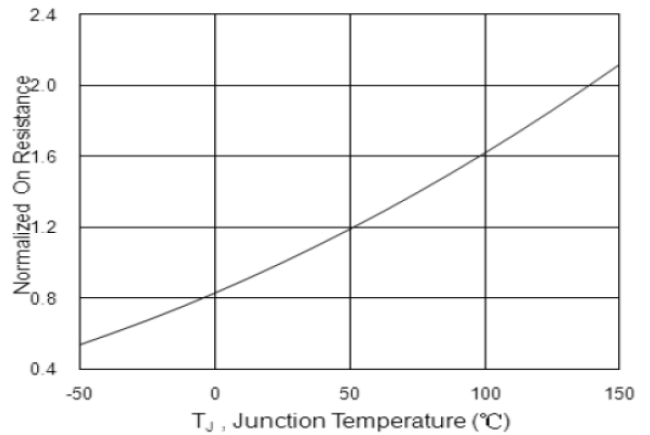


Fig.6 Normalized $R_{DS(ON)}$ v.s T_J

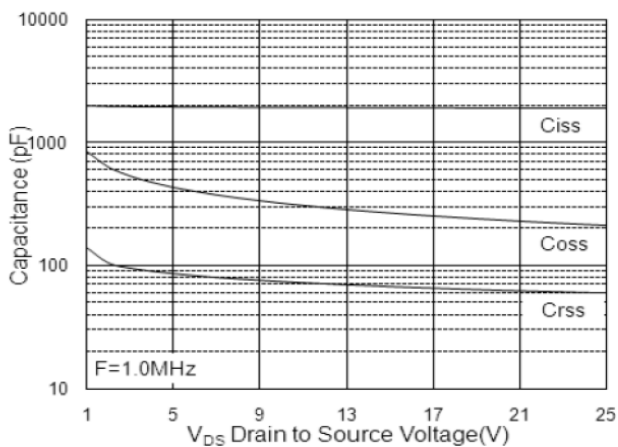


Fig.7 Capacitance

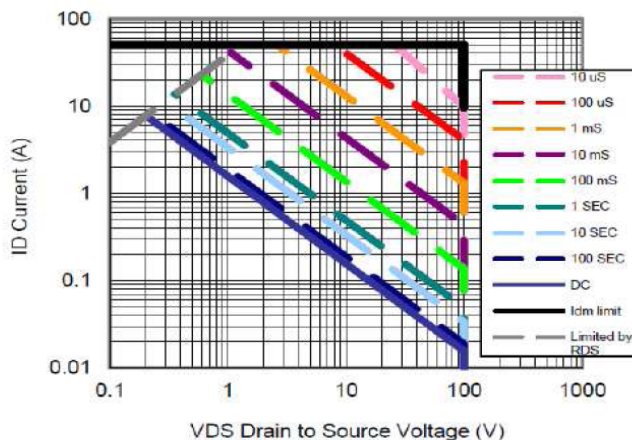


Fig.8 Safe Operating Area

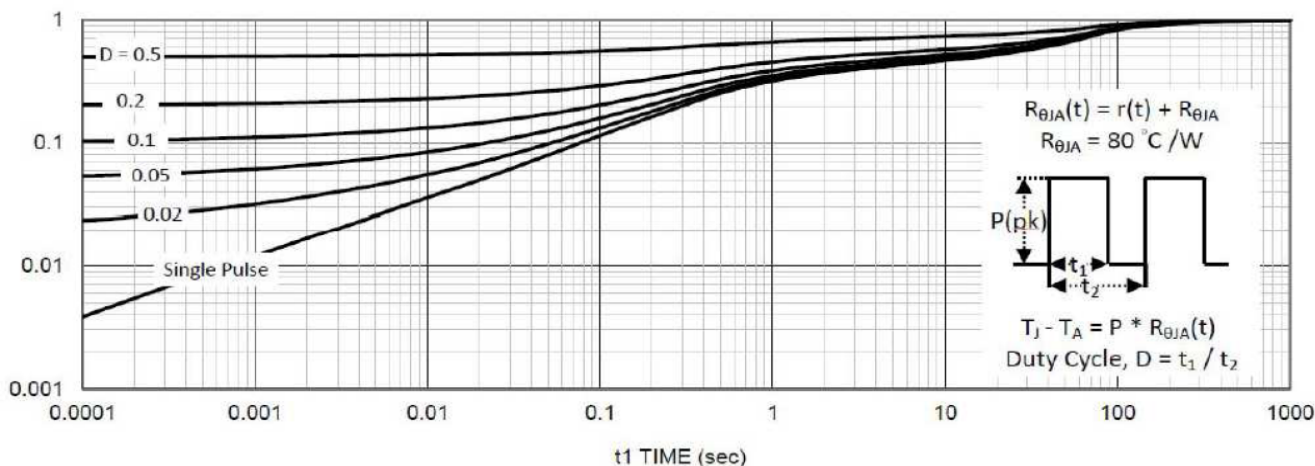


Fig.9 Normalized Maximum Transient Thermal Impedance

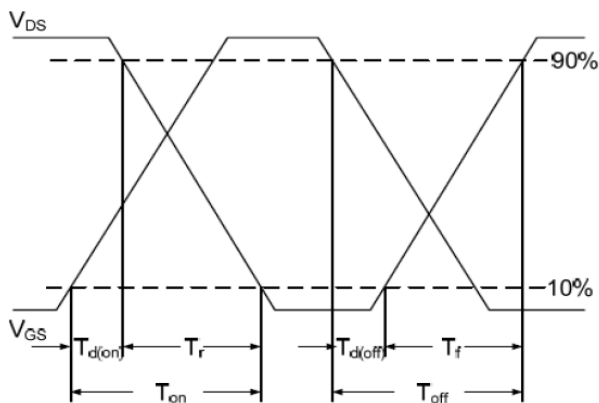


Fig.10 Switching Time Waveform

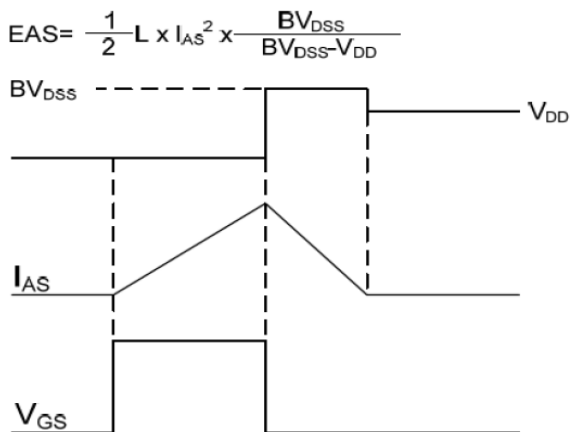


Fig.11 Unclamped Inductive Switching Waveform